

**Search Notes**

Application/Control No.

09/818,567

Examiner

Ellen C. Tran

Applicant(s)/Patent under  
Reexamination

FURUYA ET AL.

Art Unit

2134

**SEARCHED**

Class	Subclass	Date	Examiner
380	259	7/31/2006	ECT
380	210	7/31/2006	ECT
713	193	7/31/2006	ECT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search		7/31/2006	ECT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	7/31/2006	ECT
NPL - IEEE XPLORE	7/31/2006	ECT